

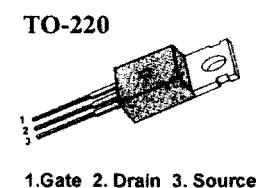
Advanced Power MOSFET

SSP7N80A

FEATURES

- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Lower Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current : $25\mu A$ (Max.) @ $V_{DS} = 800V$
- Low $R_{DS(on)}$: 1.472Ω (Typ.)

$BV_{DSS} = 800 V$
 $R_{DS(on)} = 1.8 \Omega$
 $I_D = 7 A$



Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	800	V
I_D	Continuous Drain Current ($T_C=25^\circ C$)	7	A
	Continuous Drain Current ($T_C=100^\circ C$)	4.4	
I_{DM}	Drain Current-Pulsed ①	28	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy ②	523	mJ
I_{AR}	Avalanche Current ③	7	A
E_{AR}	Repetitive Avalanche Energy ③	16	mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.0	V/ns
P_D	Total Power Dissipation ($T_C=25^\circ C$)	160	W
	Linear Derating Factor	1.28	W/C
T_J, T_{STG}	Operating Junction and Storage Temperature Range	- 55 to + 150	°C
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	0.78	°C/W
$R_{\theta CS}$	Case-to-Sink	0.5	--	
$R_{\theta JA}$	Junction-to-Ambient	--	62.5	

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SAMSS00124

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Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	800	--	--	V	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.	--	0.93	--	V/ $^\circ\text{C}$	$I_D=250\mu\text{A}$ See Fig 7
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	--	3.5	V	$V_{DS}=5\text{V}, I_D=250\mu\text{A}$
I_{GSS}	Gate-Source Leakage, Forward	--	--	100	nA	$V_{GS}=30\text{V}$
	Gate-Source Leakage, Reverse	--	--	-100		$V_{GS}=-30\text{V}$
I_{DSS}	Drain-to-Source Leakage Current	--	--	25	μA	$V_{DS}=800\text{V}$
		--	--	250		$V_{DS}=640\text{V}, T_C=125^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-State Resistance	--	--	1.8	Ω	$V_{GS}=10\text{V}, I_D=0.85\text{A}$ ④*
g_{fs}	Forward Transconductance	--	4.95	--	S	$V_{DS}=50\text{V}, I_D=0.85\text{A}$ ④
C_{iss}	Input Capacitance	--	1500	1950	pF	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$ See Fig 5
C_{oss}	Output Capacitance	--	140	165		
C_{rss}	Reverse Transfer Capacitance	--	57	66		
$t_{d(on)}$	Turn-On Delay Time	--	23	55	ns	$V_{DD}=400\text{V}, I_D=2\text{A}, R_G=16\Omega$ See Fig 13 ④ ⑤
t_r	Rise Time	--	40	90		
$t_{d(off)}$	Turn-Off Delay Time	--	92	195		
t_f	Fall Time	--	34	80		
Q_g	Total Gate Charge	--	67	88	nC	$V_{DS}=640\text{V}, V_{GS}=10\text{V}, I_D=2\text{A}$ See Fig 6 & Fig 12 ④ ⑤
Q_{gs}	Gate-Source Charge	--	11.2	--		
Q_{gd}	Gate-Drain("Miller") Charge	--	29.6	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_s	Continuous Source Current	--	--	7	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current ①	--	--	28		
V_{SD}	Diode Forward Voltage ④	--	--	1.4	V	$T_J=25^\circ\text{C}, I_S=7\text{A}, V_{GS}=0\text{V}$
t_{rr}	Reverse Recovery Time	--	520	--	ns	$T_J=25^\circ\text{C}, I_F=7\text{A}$ $di_F/dt=100\text{A}/\mu\text{s}$ ④
Q_{rr}	Reverse Recovery Charge	--	6.66	--	μC	

Notes :

- Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- $L=20\text{mH}, I_{AS}=7\text{A}, V_{DD}=50\text{V}, R_G=27\Omega$, Starting $T_J=25^\circ\text{C}$
- $I_{SD} \leq 7\text{A}, di/dt \leq 150\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$
- Pulse Test : Pulse Width = $250\mu\text{s}$, Duty Cycle $\leq 2\%$
- Essentially Independent of Operating Temperature

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Fig 1. Output Characteristics

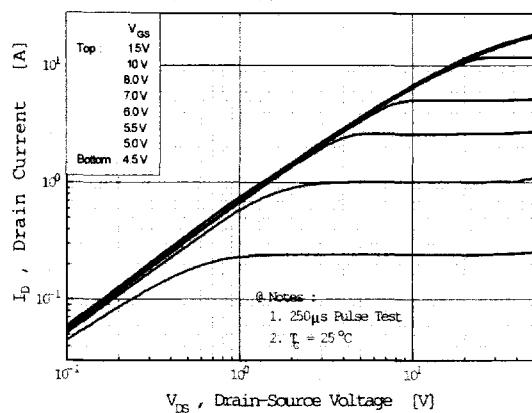


Fig 2. Transfer Characteristics

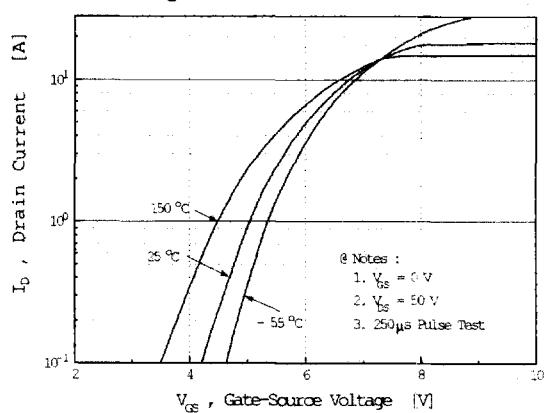


Fig 3. On-Resistance vs. Drain Current

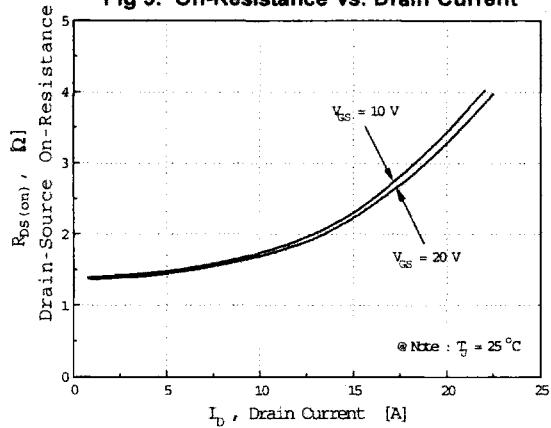


Fig 4. Source-Drain Diode Forward Voltage

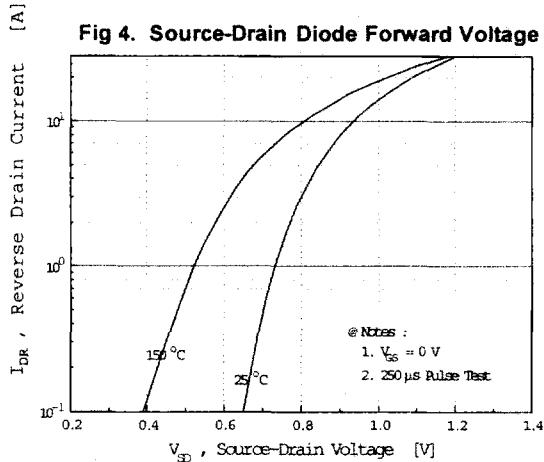


Fig 5. Capacitance vs. Drain-Source Voltage

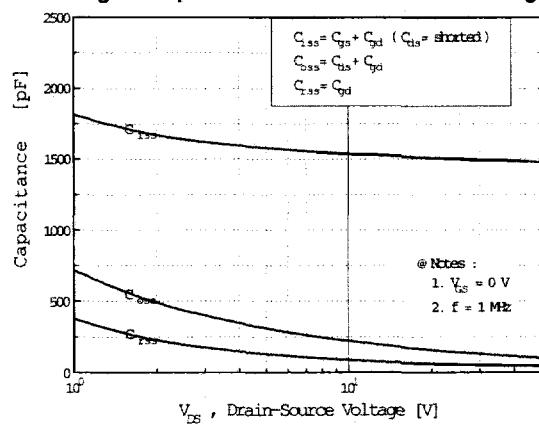
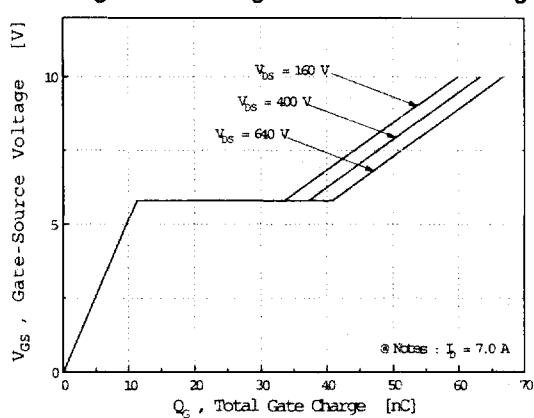
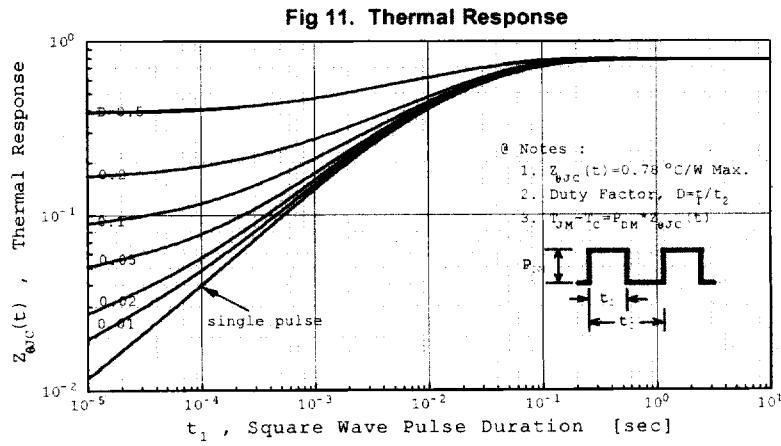
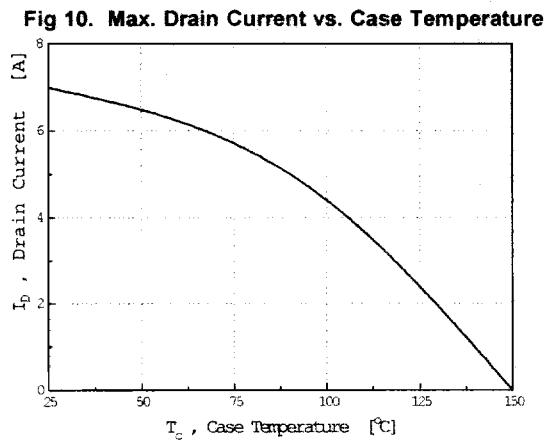
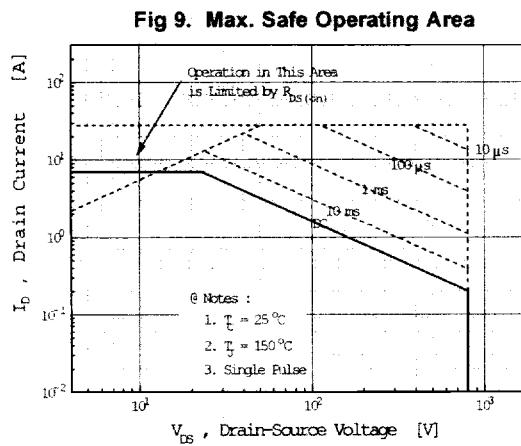
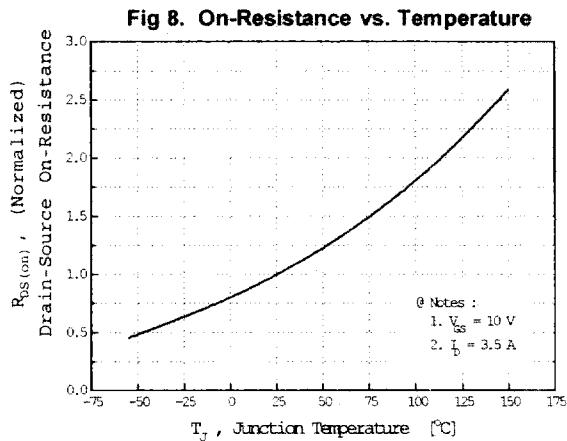
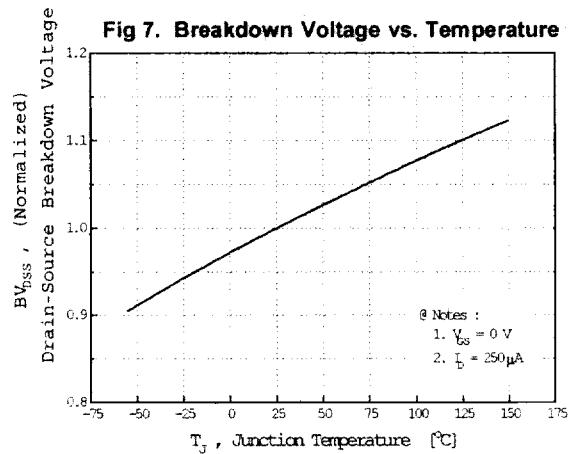


Fig 6. Gate Charge vs. Gate-Source Voltage



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Fig 12. Gate Charge Test Circuit & Waveform

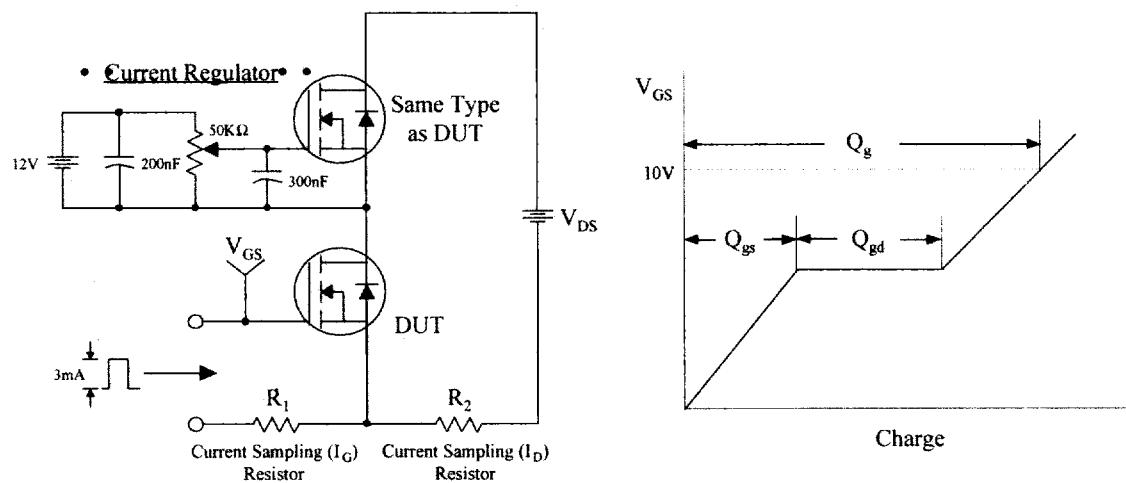


Fig 13. Resistive Switching Test Circuit & Waveforms

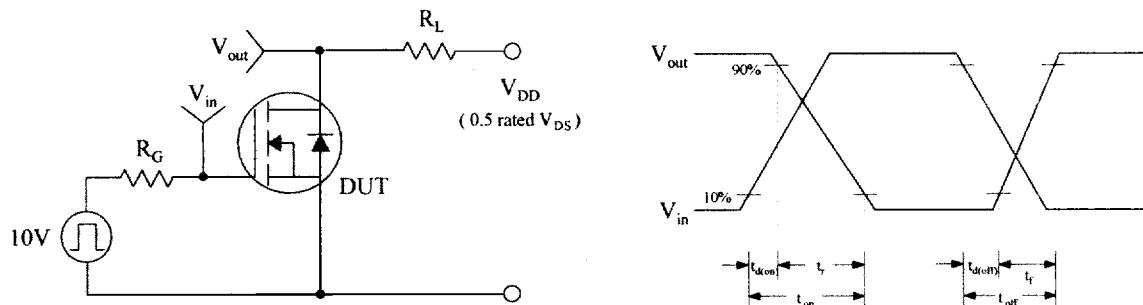
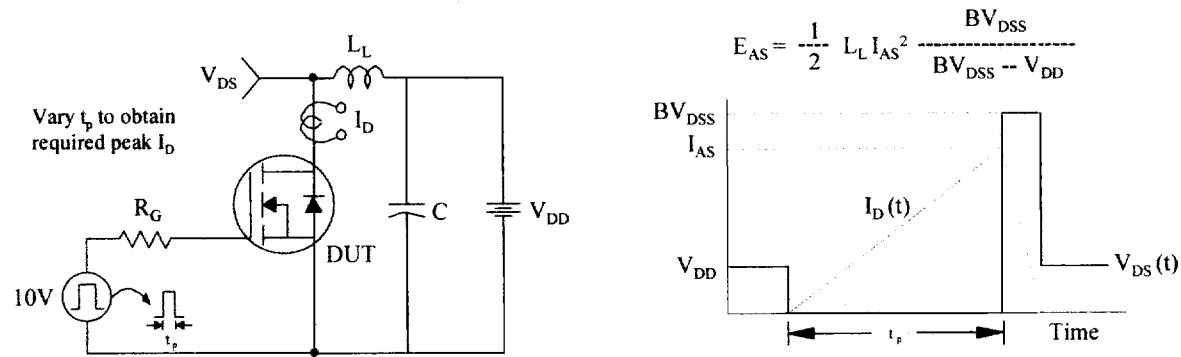


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms



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Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

